

# INTERNATIONAL STANDARD

## NORME INTERNATIONALE

**Semiconductor devices – Mechanical and climatic test methods –  
Part 39: Measurement of moisture diffusivity and water solubility in organic  
materials used for semiconductor components**

**Dispositifs à semiconducteurs – Méthodes d’essais mécaniques et  
climatiques –  
Partie 39: Mesure de la diffusivité d’humidité et de l’hydrosolubilité dans les  
matériaux organiques utilisés dans les composants à semiconducteurs**





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INTERNATIONAL  
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ICS 31.080.01

ISBN 978-2-8322-1046-7

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SEMICONDUCTOR DEVICES –  
MECHANICAL AND CLIMATIC TEST METHODS –****Part 39: Measurement of moisture diffusivity and water solubility in  
organic materials used for semiconductor components**

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This edition includes the following significant technical changes with respect to the previous edition:

- a) updated procedure for "dry weight" determination.

The text of this International Standard is based on the following documents:

Draft	Report on voting
47/2652/CDV	47/2725/RVC

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at [www.iec.ch/members\\_experts/refdocs](http://www.iec.ch/members_experts/refdocs). The main document types developed by IEC are described in greater detail at [www.iec.ch/standardsdev/publications](http://www.iec.ch/standardsdev/publications).

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